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Contents

Preface

Chapter 1: Dynamical theory

1—12 The dynamical theory of electron diffraction  
A Howie

13—17 Band theory in high-energy electron diffraction and the zone axis critical-voltage effect  
B F Buxton and P T Tremewan

18—22 Diffraction patterns in an axial direction and structure of the dispersion surfaces in cross-grating orientation  
Y Uchida, F Fujimoto, K-H Katerbau and M Wilkens

23—28 Linear combinations of Gauss-type orbitals and plane waves in the many-beam problem of high-energy electron diffraction  
K Kambe

29—33 On the correspondence between atomic or molecular orbitals and Bloch functions in 2-d high-energy electron diffraction  
B F Buxton, J E Loveluck and J W Steeds

34—40 Algebraic approaches to N-beam theory  
A C Hurley, A WS Johnson, A FMoodie, P Rez and J R Sellar

41—46 A comparison of multislice and many-beam calculations  
M D Shannon

47—49 Perturbation calculations in Bethe’s dynamical theory of electron diffraction  
A Hussein and H Wagenfeld

50—56 Electron diffraction contrast in the non-symmetric Laue case  
D K Saldin, M J Whelan and C J Rossouw

57—60 Comparison of conventional and scanning transmission electron microscopy, with particular reference to atom images under dark field  
R Uyeda and N Tanaka

61—67 Multiple inelastic scattering and dynamical diffraction  
P Rez

68—73 A transmission study of 15 MeV electrons in silicon single crystals  
E Worm, U Schiebel, A Neufert and G Clausnitzer

74—78 Experimental aspects of electron channelling patterns in scanning electron microscopy  
T Yamamoto
Contents

79—83 The origin of the defect Kikuchi band from a thin crystal in electron diffraction
Y Nakai

84—87 Anomalous contrast of Kikuchi bands in RHEED from evaporated thin layers on Ge
Y Ishikawa, T Hanabus, T Kawamura and T Ichinokawa

Chapter 2: Diffuse scattering

88—97 Short-range-order diffuse scattering from disordered alloys
INVITED D Watanabe

98—103 Disordering of Mg3Cd under electron irradiation
E P Butler

104—108 The analysis of short-range order in some doped fluorite ceramics by electron diffraction
B Hudson and P T Moseley

109—115 Dynamical diffraction from periodic arrays of dislocations
P Rez

Chapter 3: Structure factor and symmetry determination

116—128 Accurate structure factor and symmetry determination
INVITED P Goodman

129—134 Convergent-beam diffraction in the Oxford high-voltage electron microscope
A F Moodie, C J Humphreys, D Imeson and J R Sellar

135—139 On the observation of dynamically forbidden lines in two- and three-dimensional electron diffraction
J W Steeds, G M Rackham and M D Shannon

140—144 Analysis of electron diffraction Kossel patterns
A Ichimiya and G Lehmpfuhl

145—149 The crystal potential in electron diffraction and in band theory
D J Smart and C J Humphreys

150—155 Theoretical and experimental studies of Bloch wave channelling
J Gjønnes and J Taftø

156—166 Crystal structure determination using electron diffraction
INVITED J M Cowley

167—171 Determination of crystal structure factors and temperature parameters by using dynamical effects in electron diffraction
H Hirono, K Mihama and A Ichimiya
Contents

172—177 The study of topochemical conversions and phase transitions in organic molecular crystals by electron diffraction
  G M Parkinson, W Rees, M J Goringe, W Jones, S Ramdas, J M Thomas and J O Williams

178—181 Electron diffraction from a metastable phase of gold and germanium (gold 27 at.% germanium)
  G M Rackham and J W Steeds

182—187 Electron diffraction patterns and high-resolution imaging from long-period polytypes in rare-earth trialuminides
  M Gasgnier, G Schiffmacher and P Caro

188—194 Fine structure of the flux distribution of electron waves in crystal lattices near Bragg reflecting conditions
  H Hashimoto and H Endoh

195—200 Accurate crystallographic information from precipitates in 316 and related stainless steels
  K E Cooke, N Evans, L Stoter and J W Steeds

201—204 On the relationship between string integrals and the appearance of c B and b c zone axis patterns
  K K Fung and J W Steeds

Chapter 4: Low-energy electron diffraction

205—217 Advances in leed theory
  INVITED J B Pendry

218—222 Temperature dependence of the leed Kikuchi pattern and surface reconstruction of MgO (001) cleavage face
  Y Murata and S Murakami

223—227 The variation of secondary electron emission under surface state resonance conditions in meed
  T Kawamura, T Ichinokawa, Y Watanabe and H Wada

228—232 Surface state resonance of the Kikuchi pattern in low-energy electron diffraction
  S Murakami and Y Murata

233—238 Secondary electron emission spectroscopy in relation to low-energy electron diffraction
  R F Willis

239—253 Electron diffraction in the medium-energy range
  INVITED D Aberdam

254 Experimental and theoretical leed spectra from W (001)
  J Kirschner and R Feder
## Contents

<table>
<thead>
<tr>
<th>Page Range</th>
<th>Title</th>
<th>Authors</th>
</tr>
</thead>
<tbody>
<tr>
<td>255–260</td>
<td>Inelastic LEED at the beam emergence condition: Al (100)</td>
<td>A E Hughes, K Senkiw and P J Dobson</td>
</tr>
<tr>
<td>261–269</td>
<td>Low-energy electron diffraction from disordered surfaces</td>
<td>W Moritz</td>
</tr>
<tr>
<td>270–280</td>
<td>A review of surface crystallography by low-energy electron diffraction</td>
<td>INVITED S Y Tong</td>
</tr>
<tr>
<td>281–286</td>
<td>Electron spin polarisation in LEED from Au (110)</td>
<td>Ν Müller, D Wolf and R Feder</td>
</tr>
<tr>
<td>287–294</td>
<td>Polarised LEED using a GaAs spin polarised electron source</td>
<td>WN Unertl, R J Celotta and D T Pierce</td>
</tr>
</tbody>
</table>

Chapter 5: Instrumentation

<table>
<thead>
<tr>
<th>Page Range</th>
<th>Title</th>
<th>Authors</th>
</tr>
</thead>
<tbody>
<tr>
<td>295–312</td>
<td>Instrumentation for electron diffraction</td>
<td>INVITED T Mulvey</td>
</tr>
<tr>
<td>313–318</td>
<td>RHEED and THEED patterns and dark-field microscopy in a UHV SEM</td>
<td>J A Venables, C J Harland and A P Janssen</td>
</tr>
<tr>
<td>319–323</td>
<td>The application of a digital scanning electron diffractometer to radiation-sensitive materials</td>
<td>W R K Clark, J N Chapman, A M MacLeod and R P Ferrier</td>
</tr>
<tr>
<td>324–328</td>
<td>The use of channel electron multipliers in gas electron diffraction experiments of short duration</td>
<td>A P Rood</td>
</tr>
<tr>
<td>329–334</td>
<td>Measurement of THEED intensity from adsorbed xenon monolayers</td>
<td>PS Schabes-Retchkiman and J A Venables</td>
</tr>
</tbody>
</table>

Chapter 6: Defect structure

<table>
<thead>
<tr>
<th>Page Range</th>
<th>Title</th>
<th>Authors</th>
</tr>
</thead>
<tbody>
<tr>
<td>335–349</td>
<td>Study of crystal defects by diffraction contrast in the electron microscope</td>
<td>INVITED P B Hirsch</td>
</tr>
<tr>
<td>350–356</td>
<td>The nature and geometry of irradiation-induced defects in copper, molybdenum and zirconium</td>
<td>D K Saldin, A Y Stathopoulos and M J Whelan</td>
</tr>
<tr>
<td>357–362</td>
<td>The study of grain-boundary dislocations</td>
<td>R C Pond</td>
</tr>
<tr>
<td>363–369</td>
<td>Effects of interdiffusion on the misfit dislocation configuration and the moiré patterns of thin bimetallic films</td>
<td>AM Beers, EJ Mittemeijer and R Delhez</td>
</tr>
</tbody>
</table>
Contents

370–374 HVEM in situ observations of dynamical behaviour of dislocations
T Imura, H Saka and K Noda

375–380 Direct observation of the displacement cascades in Cu₃Au produced by fast-neutron irradiation
M L Jenkins, C A English and J M Titchmarsh

381–386 Theoretical and experimental images of small dislocation loops in BCC materials
C A English, B L Eyre, S M Holmes and R C Perrin

387–390 Interpretation of crystallographic structure domains obtained at low temperature in vanadium sesquioxides
R Ayroles and C Roucau

391–395 Many-beam diffraction contrast for two-dimensional defects in crystals: application to merohedral twins
M Fayard, D Gratias, R Portier and M Guymont

396 An electron diffraction study of dislocation glide and climb in double heterostructure (DH) GaAs material
G R Woolhouse and B Monemar

Chapter 7: Miscellaneous

397–401 Reflection electron diffraction on silicon carbide crystals: new developments for the study of polytypism
J-P Gauthier and P Michel

402–410 Electron microscopy and electron diffraction of electron-sensitive materials
L W Hobbs, D G Howitt and T E Mitchell

411–415 Information from rutile catalyst particles by convergent-beam electron diffraction
M D Shannon and J A Eades

416–422 The microstructure and micromechanisms of deformation in polyethylene single crystals and spherulites
P Allan, M Bevis, A Low and D Vesely

423–429 Developments in liquid electron diffraction
E Kálmán

430–434 An electron diffraction study of liquid metals
A S Brah, P J Dobson, N H March, B A Unvala and L Virdhee

435–440 A double-crystal electron interferometer
G M Rackham, J E Loveluck and J W Steeds

441–442 Author Index
Low-energy electron diffraction from disordered surfaces

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Abstract. Model calculations are presented of LEED intensities diffracted by a one-dimensionally disordered overlayer adsorbed on a well ordered substrate. Multiple scattering amplitudes are calculated by an extension of Beeby's multiple scattering method. The surface layers are divided into overlapping configurations of atoms, the diffraction of each of which is described by individual scattering amplitudes. In this way the surrounding of each adsorbed atom is divided into two parts: the immediate vicinity, in which multiple scattering is treated self-consistently, and the outer region which is represented by an averaged T matrix. The results of the model calculations indicate that the intensities are not correctly described if only averaged T matrices are used, and that in a first approximation the half-widths of the diffuse streaks observed in the experiment can be analysed using the kinematic theory.

1. Introduction

The investigation of adsorption phenomena on surfaces and surface reactions by means of low-energy electron diffraction shows that disordered structures are predominant. LEED provides a readily accessible tool in the experimental observation of lateral interactions between adsorbed atoms and two-dimensional phase transitions, which have recently become of theoretical interest (Doyen and Ertl 1975, Binder and Landau 1976). However, there remain some uncertainties in the usual interpretation of diffuse LEED patterns which neglect multiple scattering effects. It has been assumed that multiple scattering effects are unimportant as long as only the half-widths of the diffuse peaks are studied as a function of temperature and coverage with fixed energy and angles of incidence of the primary beam (Estrup and Anderson 1967, McKee et al 1973, Gerlach and Rhodin 1969, Carroll 1972, Ertl and Plancher 1975, Park and Houston 1969, Houston and Park 1970, 1971, Cowley and Shuman 1973, Ertl and Küppers 1970). The results of a few model calculations presented in this paper show that this assumption is rather well justified, and to a first approximation the half-widths of the strong peaks remain unchanged compared to the kinematic calculation and can be used to determine the statistical parameters by direct evaluation of the measured reflex profile. The shape of the angular profile may be strongly deformed by multiple scattering effects and, of course, a multiple scattering theory is necessary to get a correct description of the intensities (e.g. of the intensity changes during a phase transition) or if the calculated intensities of diffuse streaks have to be compared with the experiment in order to decide between two or more possible structure models.

The calculation of multiple scattering amplitudes from disordered surfaces can be done by an extension of Beeby's T matrix formalism (Beeby 1968). The surface layers
are divided into overlapping configurations of atoms; the diffraction of each configuration
is described by individual scattering amplitudes. In this way multiple scattering within
the ordered substrate and the area of the adsorbed layer (as described above) is treated
self-consistently, while an averaged scattering amplitude is taken for the remaining
contributions. The use of configurations of atoms also has the advantage that statistical
models, including nearest-neighbour and next-nearest-neighbour interactions, and even
interactions between atoms further apart, can be used in the multiple scattering
formalism.

Once the scattering amplitudes are calculated, the determination of the intensities
and the angular reflection profiles follows the same lines as already described in the
theory of diffuse x-ray diffraction (Jagodzinski et al 1978).

2. Model of the surface

The lattice-gas model is a reasonable model to describe a disordered adsorbed over-
layer, and the specific model used here shows disorder in one direction only for the
sake of simplicity (figure 1). The restriction to one-dimensional disorder is advantageous
in that the correlation functions can be calculated analytically and an analytical

expression exists for the backscattered intensity. It is not believed that two-dimensional
disorder produces completely new effects in the angular profiles. In addition, one-
dimensionally disordered overlayers are quite frequently realised, such as oxygen on
W(112) (McKee et al 1973, Ertl and Plancher 1975) and Ag(110) (Bradshaw et al
1972), Na on Ni(110) (Gerlach and Rhodin 1969), and the clean Au(110) surface
(Wolf et al 1978).

If only nearest-neighbour interactions are assumed, the statistical distribution of the
adsorbed chains of atoms is completely described by two parameters $\alpha_1$ and $\alpha_2$,
$p_{AA}(1) = (1 - \alpha_1), p_{AB}(1) = \alpha_1, p_{BA}(1) = \alpha_2, p_{BB}(1) = (1 - \alpha_2)$, where A denotes
an adsorbed chain and B a vacancy. $p_{AA}(1)$ denotes the probability that one chain of
adsorbed atoms is followed by another one. The a priori probabilities $p_n$ are given by the
eigenvalue equation

$$\sum_m p_m p_{mn}(1) = p_n$$
and the correlation functions for all distances \( j_a \) are simply given by \( p_{mn}(j) = [P(1)]_{mn}^j \) (where \( j = 1, 2 \ldots \)) using the matrix

\[
P(1) = \begin{pmatrix}
  p_{AA} & p_{AB} \\
  p_{BA} & p_{BB}
\end{pmatrix}.
\]

The correlation functions \( p_{mn}(j) \) may also be expressed in terms of the eigenvalues \( \lambda_r \) of the matrix \( P(1) \) (Jagodzinski 1949, 1954)

\[
p_{mn}(j) = \sum_r c_{mn}^{(r)} \lambda_r^j
\]

in order to render summable the expression for the interference of amplitudes. The kind and position of diffuse peaks in the diffraction pattern is determined by the eigenvalues \( \lambda \), which are generally complex and of modulus \( |\lambda| < 1 \). A detailed discussion on that topic is given by Jagodzinski et al (1978). In order to include next-nearest-neighbour interactions, four parameters are needed for describing the distribution of adsorbed chains: \( p_{AAA} = \alpha_1, p_{ABA} = \alpha_2, p_{BAA} = \alpha_3, p_{BBA} = \alpha_4 \). This results in an enlarged matrix \( P(1) \) and four eigenvalues \( \lambda \), by which a \( 4 \times 1 \) superstructure can be described.

The probabilities mentioned above are related to the occupancy of lattice sites by adsorbed atoms and can be used as input parameters in a kinematic theory of diffraction. The multiple scattering theory described below needs probabilities as input parameters, which are related to configurations of atoms, as the effective scattering amplitude is influenced by its neighbourhood. The effective scattering amplitude represents all scattering processes which end in that atom. In a first approximation only the nearest neighbours are included in these configurations and the disordered surface is constructed by overlapping configurations

| A | B | A | A | B | B | A | B | A |

Each one getting a different scattering amplitude which is related to the central atom of the configuration. The matrix of probabilities described above has therefore to be re-defined as the set of configurations:

\[
P(1) = \begin{pmatrix}
  (1-\alpha_1) & \alpha_1 & 0 & 0 & 0 & 0 & 0 & 0 \\
  0 & 0 & 0 & 0 & \alpha_2 & (1-\alpha_2) & 0 & 0 \\
  (1-\alpha_1) & \alpha_1 & 0 & 0 & 0 & 0 & 0 & 0 \\
  0 & 0 & 0 & 0 & \alpha_2 & (1-\alpha_2) & 0 & 0 \\
  0 & 0 & (1-\alpha_3) & \alpha_3 & 0 & 0 & 0 & 0 \\
  0 & 0 & 0 & 0 & 0 & \alpha_4 & (1-\alpha_4) & 0 \\
  0 & 0 & (1-\alpha_3) & \alpha_3 & 0 & 0 & 0 & 0 \\
  0 & 0 & 0 & 0 & 0 & \alpha_4 & (1-\alpha_4)
\end{pmatrix}
\]
This matrix becomes degenerate, still having the same eigenvalues \( \lambda_1 \) to \( \lambda_4 \), while \( \lambda_5 \) to \( \lambda_8 \) vanish. Of course, this is independent of the size of the configuration and the dimensions of the matrix, as long as the same surface is described.

The connection between the probabilities or correlation functions and thermodynamic quantities like interaction energies etc will not be discussed here, as we only need those probabilities which can be determined by comparison with the experimental diffraction picture.

3. Multiple scattering theory

Since the details of the theory are given elsewhere (Moritz et al 1978), only a brief description will be outlined here. As mentioned above, the effect of multiple scattering is that each atom with a different neighbourhood gets a different scattering amplitude, which becomes explicitly dependent on the incoming and outgoing wave vectors \( k \) and \( k' \). Within a single layer the contribution from the neighbouring atoms to the total scattering amplitude is so strong in most cases that a series expansion fails, while between the layers the strong damping above the plasmon threshold permits perturbative methods (Pendry 1971). For intra-layer scattering the sum over lattice points is best done in direct space and, usually, all lattice points within a circle of about 10–15 interatomic distances have to be included to reach convergence. However, the main contribution arises from single scattering and multiple scattering between nearest or next-nearest neighbours (Moritz et al 1978). These principles remain valid in the case of both ordered and disordered surfaces.

On a disordered surface there are no equivalent sites and the scattering from a layer or a subplane cannot be represented by a single \( T \) matrix. In order to facilitate the solution of the problem the averaged \( T \) matrix approximation (Ehrenreich and Schwartz 1976) – well known in the theory of the electronic structure of binary alloys – could be used. It is also employed by Duke and Liebsch (1974) in their application to disordered overlayers. In their work the main difficulty arises in trying to incorporate correctly short-range order in the multiple scattering series. In the method used here the surrounding of an atom is divided into an ‘area of multiple scattering’, which includes nearest or next-nearest neighbours, and the outside region, which is represented by an averaged \( T \) matrix. For each of the possible configurations inside the ‘area of multiple scattering’ a different scattering amplitude is calculated. In this way two main difficulties are overcome. First, the most important part of the multiple scattering amplitude (caused by the immediate vicinity of an atom) is treated self-consistently, and second, there is no restriction to a random distribution of the adsorbed atoms (high-temperature limit) as any statistical model is easily incorporated in the multiple scattering formalism.

The formalism best suited for introducing disorder is the \( T \) matrix method as given by Beeby (1968), where the sum over lattice points and layers is done in real space, which has the advantage that the \( T \) matrices themselves depend only on the incoming wave vector \( k \), and the set of equations has to be solved only once to get the intensities in all outgoing directions \( k' \).
The final formula is given by

\[ T_{m,\nu}^{m,\nu}(k) = t_{m,\nu}(k) + t_{m,\nu}(k) \sum_{\mu} \sum_{n} G_{m,n}^{\mu\nu}(k) T_{n,\mu}^{m,\nu}(k) \]

\[ G_{m,n}^{\mu\nu}(k) = \sum_{R} G(R + d_{\mu} - d_{\nu}) \exp[-i k(R + d_{\mu} - d_{\nu})] p_{m,n}(R) \]

\[ + \sum_{R} G(R + d_{\mu} - d_{\nu}) \exp[-i k(R + d_{\mu} - d_{\nu})] p_{n} \]

(4)

where the indices \(\nu, \mu\) denote the different layers, and the indices \(n, m\) stand for the different configurations. \(p_{m,n}(R)\) are the sequence probabilities as given in equation (3) and, for convenience, the angular momentum indices \(L, L'\) of the electron propagator matrices and the scattering matrices have been suppressed. For the special model of a half-covered surface, one sort of adsorbate atoms and \(N\) possible configurations, the atomic scattering matrices are

\[
t_{\nu}^{m}(k) = \begin{cases} 
(1/k) \exp(i \delta_{\nu}^{L,A}) \sin \delta_{\nu}^{L,A} \delta_{L,L'} & (\nu = 1, m = 1, \ldots, N/2) \\
0 & (\nu = 1, m = (N/2) + 1, \ldots, N) \\
(1/k) \exp(i \delta_{\nu}^{L,S}) \sin \delta_{\nu}^{L,S} \delta_{L,L'} & (\nu \geq 2).
\end{cases}
\]

(5)

\(\delta_{\nu}^{L,A}\) and \(\delta_{\nu}^{L,S}\) are the phase shifts of the adsorbate and substrate respectively. The system of equations (4) is not solved directly because of the dimension of the matrix to be inverted. Therefore a perturbative solution has been used in which first an averaged \(T\) matrix is calculated and then the deviations from the average are obtained by an iteration scheme described in the appendix of the work by Moritz et al (1978).

The diffracted intensity can be written (Jagodzinski et al 1978) as

\[ I(k, k') = R M \sum_{j} \overline{FF}_{j}^{*} \exp[-i(k-k') \cdot a_{j}] \]

(6)

where \(R_{L}\) is a normalisation factor, \(M\) the number of unit cells, and \(\overline{FF}_{j}^{*}\) the averaged structure factors

\[ \overline{FF}_{j}^{*} = \sum_{m,n} p_{m} p_{m,n}(j) F_{m}(k, k') F_{n}^{*}(k, k'). \]

(7)

\(F_{m}(k, k')\) represents a generalised structure amplitude and contains the sum over layers:

\[ F_{m}(k, k') = \sum_{L, L'} Y_{L}^{*}(\Omega_{k'}) T_{L,\nu}^{m,\nu}(k) Y_{L'}^{*}(\Omega_{k}) \exp[i(k-k')d_{\nu}]. \]

(8)

Using equation (2)

\[ \overline{FF}_{j}^{*} = \sum_{m,n} \sum_{r} C_{m,n}^{(r)} \lambda_{r}^{j} F_{m} F_{n}^{*} = \sum_{r} (B_{r} + i D_{r}) \lambda_{r}^{j} \]

(9)
the final formula for the diffracted intensity from the surface disordered in the x direction only is given (Jagodzinski 1949, 1954) by

\[
I(k, k') = R_R M \left\{ \sum_{r}^{1,N} B_r \frac{1 - |\lambda_r|^2}{1 - 2|\lambda_r| \cos(A_1 + \phi_r) + |\lambda_r|^2} - 2D_r \frac{|\lambda_r| \sin(A_1 + \phi_r)}{1 - 2|\lambda_r|^2 \cos(A_1 + \phi_r) + |\lambda_r|^2} \right\} \delta(k_y - k'_y + g_y)
\]

where

\[
A_1 = (k - k') \cdot a
\]

\[
\lambda_r = |\lambda_r| \exp(i \phi_r)
\]

4. Results and discussion

Two different models of disorder have been studied. In the first model \(\alpha_1 = \alpha_2 = \alpha_3 = \alpha_4 = 0.8\) is assumed, which represents a half-covered surface with repulsive interactions between the adsorbed atoms (NN interactions only) and results in a \((2 \times 1)\) superstructure with broadened half-order and sharp integer-order reflections. In the second model, interactions between next-nearest neighbours have been added by setting \(\alpha_1 = \alpha_4 = 0.8\) and \(\alpha_2 = \alpha_3 = 0.4\). The surface is still half-covered and mainly

![Figure 2](image)

**Figure 2.** Kinematically calculated intensities showing the influence of the atomic differential cross section on angular reflection profiles. \(\alpha_1 = \alpha_2 = \alpha_3 = \alpha_4 = 0.8, E_p = 50\) eV, \(V_i = 4\) eV, normal incidence: \(\cdots \cdot \cdot \cdot \) 1 phase shift (s-wave scattering); \(\cdots \cdot \cdot \cdot \) three phase shifts; \(\cdots \cdot \cdot \cdot \) four phase shifts. The position of the sharp integer-order reflections is indicated by the vertical lines.
Figure 3. Dynamically calculated angular profiles for same model as in figure 2, taking into account four phase shifts and five layers: nearest neighbours are included in the configurations for the uppermost three layers; averaged T matrices are used for all layers; as in figure 2, without intensity scale.

pairs of chains are formed, resulting approximately in a (4 x 1) superstructure. The (110) face of silver has been chosen as substrate and the same phase shifts have been used for adsorbate and substrate, as different phase shifts do not seem to be relevant in these model calculations. Up to four phase shifts have been taken into account, which should be sufficient at 50 eV primary-beam energy. The crystal consists of five layers, of which the uppermost three are divided into configurations as described above; the damping parameter has been set at $V = 4$ eV.

Figure 2 shows the calculated reflection profiles with different numbers of phase shifts used. The suppression of the (3/2, 0) reflection corresponds to a deep minimum in the atomic scattering amplitude of silver at $\theta = 140^\circ$ and $E_p = 50$ eV. The dotted lines in diagrams 2–4 are obtained by single scattering and s-wave scattering only (i.e. it is simply the Fourier transform of the correlation functions and represents the 'state of order' of the surface, lacking any individual scattering properties). Figure 3 shows that through the influence of multiple scattering the (3/2, 0) reflection appears again, but this is not the case if averaged T matrices only are used (broken curve). In that approximation the size of the configurations has shrunk to a single atom and the scattering properties of an adsorbed atom are described by a single T matrix. This approximation is not sufficient to describe the intensities correctly.

For comparing the width of line profiles at half-intensities, even a kinematic calculation is sufficient. All prominent peaks show mainly the same shape; the very weak peaks are not used anyway in an experimental investigation. The same features are obtained with the second statistical model shown in figure 4. With different energies, rather different peak profiles are obtained. Nevertheless, the conclusion may be drawn that in an experiment the proper half-widths (that of the dotted line) could be measured approximately. However, the correct description of the intensities is only possible
Figure 4. Dynamically calculated angular profiles at two different energies of the incident beam. Nearest neighbours are included in the configuration for the first three layers, and three phase shifts are used. $E_p = 50$ eV; $E_p = 70$ eV. The statistical model includes next-nearest-neighbour interactions $\alpha_1 = \alpha_2 = 0.8, \alpha_3 = \alpha_4 = 0.4$. Kinematic calculation with s-wave scattering.

Figure 5. Convergence of the iteration procedure by which equation (4) is solved (same conditions as in figure 3): four iterations; five iterations; seven iterations.
accuracy of 10%, which means that a direct solution would have been more efficient. The convergence of the iteration procedure is shown in figure 5.

In the few model calculations presented here only the nearest neighbours are included and this is probably not sufficient. Inclusion of the next-nearest neighbours is possible by making use of the symmetry properties of the propagator matrices at normal incidence and the degeneracy of the matrix of probabilities.

References

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